

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Ching Y. Suen et al.

Application No.: Unassigned

Group Art Unit: Unassigned

Filed: February 26, 2004

Examiner: Unassigned

For: APPARATUS AND METHOD FOR CHARACTER RECOGNITION AND PROGRAM
THEREOF

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure provisions of 37 CFR § 1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the subject application.

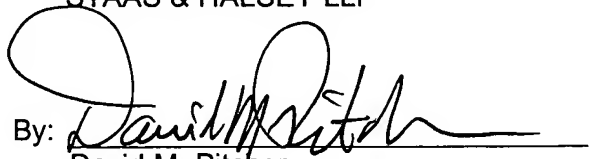
1. Enclosures accompanying this Information Disclosure Statement are:
 - 1a. ☒ Form PTO-1449.
 - 1b. ☒ Copies of IDS citations.
 - 1c. ☐ An English language copy of search report(s) from a counterpart foreign application or a PCT International Search Report.
 - 1d. ☐ English language translation (complete or relevant portion(s)) attached to each non-English language publication.
 - 1e. ☒ Explanations of Relevancy of References (ATTACHMENT 1(e), hereto) for providing a concise explanation of each non-English publication.
2. ☒ In accordance with 37 CFR § 1.98, a concise explanation of what is presently understood to be the relevance of each non-English language publication is

(Check appropriate Items 2a, 2b, 2c and/or 2d)
 - 2a. ☐ satisfied because all non-English language publications were cited on the enclosed "English-language version of the search report or action which indicates the degree of relevance found by the foreign office". (See MPEP 609, Minimum Requirements for an Information Disclosure Statement, Part A(3): Concise Explanation of Relevance, pp. 600-100 to 600-101, Rev. 1, Feb. 2000.)
 - 2b. ☒ set forth in the application.

- 2c. ☐ satisfied because an English language translation (complete or relevant portion(s)) is attached to each non-English language publication.
- 2d. ☒ enclosed as Attachment 1(e), hereto.
3. No admission is made that the information cited in this Statement is, or is considered to be, material to patentability nor a representation that a search has been made (other than search report(s) from a counterpart foreign application or a PCT International Search Report, if submitted herewith). 37 CFR §§ 1.97(g) and (h).

Respectfully submitted,

STAAS & HALSEY LLP

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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTORNEY DOCKET NO. 1391.1056	APPLICATION NO. Unassigned
LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		FIRST NAMED INVENTOR Ching Y. Suen et al.	
		FILING DATE February 26, 2004	GROUP ART UNIT Unassigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	AA	DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	<u>TRANSLATION</u> YES NO	
	AG	5-12491	01/22/93	Japan			X	
	AH							
	AI							
	AJ							

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

	AK	Simon X. LIAO et al., "On Image Analysis by Moments," IEEE Trans. on PAMI, Vol. 18, No. 3, March 1996, pp. 254-266 (March 1996).
	AL	S. SATOH et al., "Evaluation of Two Neocognitron-type Models for Recognition of Rotated Patterns," ICONIP 2000, WBP-04 (2000), pp.295-299.
	AM	Q. XIE et al., "A Construction of Pattern Recognition System Invariant to Translation, Scale-Change and Rotation Transformation of Patterns," Vol. 27, No. 10, pp. 1167-1174 (1991).
	AN	H. Hase et al., "Alignment of Free Layout Color Texts for Character Recognition," Proceeding of the Sixth International Conference on Document Analysis and Recognition, September 10-13, 2001, pp. 932-936 (Sept. 2001).
	AO	Hiroshi MURASE et al., "Three-dimensional object recognition using two-dimensional collation - parametric Eigen space techniques, IECE Trans. vol. J77-D-II, no. 11, Nov. 1994, pp.2179-2187 (Nov. 1994).

EXAMINER	DATE CONSIDERED
<small>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>	

ATTACHMENT 1(e)

EXPLANATIONS OF RELEVANCY OF REFERENCES	ATTORNEY DOCKET NO. 1391.1056	APPLICATION NO. Unassigned
	FIRST NAMED INVENTOR Ching Y. Suen et al.	
	FILING DATE February 26, 2004	GROUP ART UNIT Unassigned

References AG and AK-AO - References AG and AK-AO are cited and/or discussed in the application specification, such as at pages 1-3.